


<b>Search Notes</b>  	<b>Application/Control No.</b>  10584634	<b>Applicant(s)/Patent Under Reexamination</b>  IKEDA ET AL.
	<b>Examiner</b>  Sophie Hon	<b>Art Unit</b>  1798

SEARCHED			
Class	Subclass	Date	Examiner
428	1.3,1.32-1.33	5/23/11	SH
349	137	"	"

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search attached	5/23/11	SH
Reviewed STIC EIC Search by searcher Huang, Mei Q. dated 9/26/08	"	"
Reviewed correlated appln 11/886,258	"	"

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
428	1.3,1.32-1.33	5/23/11	SH
349	137	"	"

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